

A K M Mahfuzul Islam

List of Publications by Year in descending order

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papers

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docs citations

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116
citing authors

#	ARTICLE	IF	CITATIONS
1	An 11-nW CMOS Temperature-to-Digital Converter Utilizing Sub-Threshold Current at Sub-Thermal Drain Voltage. IEEE Journal of Solid-State Circuits, 2019, 54, 613-622.	5.4	49
2	Wide-Supply-Range All-Digital Leakage Variation Sensor for On-Chip Process and Temperature Monitoring. IEEE Journal of Solid-State Circuits, 2015, 50, 2475-2490.	5.4	41
3	Inhomogeneous Ring Oscillator for Within-Die Variability and RTN Characterization. IEEE Transactions on Semiconductor Manufacturing, 2013, 26, 296-305.	1.7	28
4	A 6.4 nW 1.7% Relative Inaccuracy CMOS Temperature Sensor Utilizing Sub-Thermal Drain Voltage Stabilization and Frequency-Locked Loop. IEEE Solid-State Circuits Letters, 2020, 3, 458-461.	2.0	13
5	Area-efficient reconfigurable ring oscillator for device and circuit level characterization of static and dynamic variations. Japanese Journal of Applied Physics, 2014, 53, 04EE08.	1.5	8
6	Statistical Analysis and Modeling of Random Telegraph Noise Based on Gate Delay Measurement. IEEE Transactions on Semiconductor Manufacturing, 2017, 30, 216-226.	1.7	7
7	Flash ADC Utilizing Offset Voltage Variation With Order Statistics Based Comparator Selection. , 2021, , .		2
8	CDF Distance Based Statistical Parameter Extraction Using Nonlinear Delay Variation Models. , 2021, , .		2
9	Low-Power Design of Digital LDO With Nonlinear Symmetric Frequency Generation. IEEE Transactions on Circuits and Systems II: Express Briefs, 2022, 69, 4644-4648.	3.0	2
10	A process scalable voltage-reference-free temperature sensor utilizing MOSFET threshold voltage variation. , 2021, , .		1
11	Order Statistics Based Low-Power Flash ADC with On-Chip Comparator Selection. IEICE Transactions on Fundamentals of Electronics, Communications and Computer Sciences, 2022, E105.A, 1450-1457.	0.3	1
12	On-chip leakage current variation measurement using external-reference-free current-to-time conversion for densely placed MOSFETs. Japanese Journal of Applied Physics, 2022, 61, SC1056.	1.5	0